

			14 Precise parameter measurements 15 Structure of polycrystalline aggregates 16 Stress measurement 17 Concluding remarks	
105/2/23~105/6/21 每週二 18:20~21:00	金屬材料與製 程	吳威德老師	01 課程介紹 02 序論 03 金屬材料總論 / 報告 04 鐵和鋼 05 鋼的熱處理 06 碳鋼 07 合金鋼 08 工具鋼 09 期中考 10 鑄鐵,鑄鐵的熱處理 11 鑄鐵的種類 12 鋼的表面硬化 13 滲碳與滲氮 14 非鐵金屬材料 15 其他金屬合金 16 複合材料 17 機械工業用主要複合材料 18 期末考	3 學分 (54 小時)
105/2/24~105/6/22 每週三 18:20~21:00	材料缺陷	呂福興老師	01 Syllabus/Introduction 02 Point defects in metallic systems: theory-vacancies and interstitials 03 Point defects in metallic systems: theory defects complexes 04 Point defects in metallic systems experimental	3 學分 (54 小時)

			<p>05 Point defects: thermal disorder in nonmetallic systems</p> <p>06 Point defects: thermal disorder in nonmetallic systems</p> <p>07 Point defects: component activity dependent disorder in nonmetallic systems (nonstoichiometric compounds)</p> <p>08 Point defects: component activity dependent disorder in nonmetallic systems (nonstoichiometric compounds)</p> <p>09 Prelim</p> <p>10 Point defects in nonstoichiometric compounds: experimental</p> <p>11 Point defects: component activity dependent disorder in nonmetallic systems</p> <p>12 Point defects: component activity dependent disorder in nonmetallic systems: dopant effects</p> <p>13 Si crystal growth and oxidation: processes and defects</p> <p>14 Dislocations/oxidation-induced stacking faults</p> <p>15 Oral report</p> <p>16 Defect etching</p> <p>17 Final remark</p>	
<p>105/2/25~105/6/23</p> <p>每週四</p> <p>18:20~21:00</p>	<p>電子顯微鏡原 理</p>	<p>林克偉老師</p>	<p>01 Microscopy with light and electrons (第 1.2 週)</p> <p>02 Electron-specimen interactions: processes and detectors (第 3.4 週)</p> <p>03 The electron microscope family (第 5.6 週)</p> <p>04 Specimen preparation for electron microscopy (第 7.8 週)</p> <p>05 Midterm exam</p> <p>06 The interpretation and analysis of micrographs (第 10.11 週)</p> <p>07 Analysis in the electron microscope (第 12.13 週)</p>	<p>3 學分</p> <p>(54 小時)</p>

			08 Specialised EM- and other microscopical and analytical techniques (第 14.15 週) 09 Examples of the use of electron microscopy (第 16.17 週) 10 Final Oral Exam	
105/2/27~105/6/25 每週六 9:10~12:00	高等元件物理	武東星老師	01 Review of Basic Semiconductor Device Physics 02 Memory devices 03 Thin film transistor devices for LCD 04 High speed devices 05 Mid-Term Examination 06 Advanced light-emitting devices 07 Advanced photovoltaic devices 08 Advanced optoelectronic devices 09 End-Term Examination	3 學分 (54 小時)